

<b>Notice of References Cited</b>	Application/Control No. 10/662,441		Applicant(s)/Patent Under Reexamination MYHREN ET AL.	
	Examiner Barbara P. Badio, Ph.D.		Art Unit 1612	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 08217787	08-1996	JP	Udagawa et al.	-
	O					
	P					
	Q					
	R					
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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	English Translation of JP08217787.
	V	English Abstract of JP08217787
	W	
	X	

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